

METHOD AND STRUCTURE FOR PICOSECOND-IMAGING-CIRCUIT-ANALYSIS BASED BUILT-IN-SELF-TEST DIAGNOSTIC

ABSTRACT

5 A method (and structure) of at least one of testing, diagnosing, and monitoring an operation of an electronic circuit, includes interrupting a clock signal used to provide a clocking for a normal operation of the circuit and using a second clock signal to repeatedly cycle through a predetermined cycle of operations for the circuit.

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